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**NATIONAL STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

GB/T 15651.6-2023

**Semiconductor devices - Part 5-6: Optoelectronic devices -
Light emitting diodes
(English Translation)**

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Foreword

This document complies with the provisions of GB/T 1.1-2020 "Standardization Work Guidelines Part 1: Structure and Drafting Rules of Standardization Documents" Drafting.

This document is Part 5-6 of GB/T 15651 "Semiconductor Devices". GB/T 15651 has published the following parts.

---Semiconductor devices, discrete devices and integrated circuits Part 5: Optoelectronic devices (GB/T 15651-1995);

--- Semiconductor discrete devices and integrated circuits Part 5-2.Basic ratings and characteristics of optoelectronic devices (GB/T 15651.2-2003);

--- Semiconductor discrete devices and integrated circuits Part 5-3.Test methods for optoelectronic devices (GB/T 15651.3-2003);

---Semiconductor Devices Discrete Devices Part 5-4.Optoelectronic Devices Semiconductor Lasers (GB/T 15651.4-2017);

This document is equivalent to IEC 60747-5-6:2021 "Semiconductor Devices Part 5-6.Optoelectronic Devices Light-Emitting Diodes".

This document has made the following minimal editorial changes.

---Add footnotes g and h in Table 1, footnote 1 in Table 2, footnote j in Table 5, footnote m in Table 6, and footnote f in Table 7.

Please note that some content in this document may be subject to patents. The publisher of this document assumes no responsibility for identifying patents.

Introduction

Parts 5-6 of the GB/T 15651 series are formulated to provide appropriate testing and evaluation of light-emitting diode products for general industrial applications.

basis.

Part 5 of the GB/T 15651 series is a series of standards for semiconductor optoelectronic devices, which mainly stipulates the overall requirements for optoelectronic devices.

Requirements, basic ratings and characteristics, test methods, semiconductor lasers, optocouplers, light emitting diodes, photodiodes and phototransistors, etc.